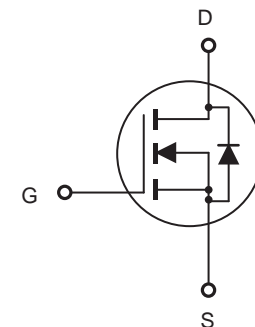
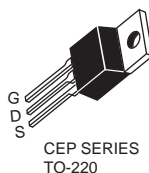
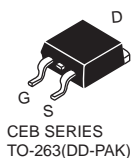


FEATURES

- 30V, 197A, $R_{DS(ON)} = 2\text{ m}\Omega$ @ $V_{GS} = 10\text{V}$.
 $R_{DS(ON)} = 3\text{ m}\Omega$ @ $V_{GS} = 4.5\text{V}$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handling capability.
- Lead-free plating ; RoHS compliant.
- TO-220 & TO-263 package.



ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	I_D	197	A
		124	A
Drain Current-Pulsed ^a	I_{DM}	788	A
Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ - Derate above 25°C	P_D	139	W
		1.1	W/ $^\circ\text{C}$
Single Pulsed Avalanche Energy ^d	E_{AS}	800	mJ
Single Pulsed Avalanche Current ^d	I_{AS}	40	A
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.9	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	$^\circ\text{C/W}$



CEP20A03/CEB20A03

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30V, V_{GS} = 0V$			1	μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{GS} = 20V, V_{DS} = 0V$			100	nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{GS} = -20V, V_{DS} = 0V$			-100	nA
On Characteristics^b						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	1		3	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 30A$		1.6	2	$m\Omega$
		$V_{GS} = 4.5V, I_D = 30A$		2	3	$m\Omega$
Gate input resistance	R_g	$f=1\text{MHz}, \text{open Drain}$		2		Ω
Dynamic Characteristics^c						
Input Capacitance	C_{iss}	$V_{DS} = 15V, V_{GS} = 0V, f = 1.0 \text{ MHz}$		7950		pF
Output Capacitance	C_{oss}			1055		pF
Reverse Transfer Capacitance	C_{rss}			740		pF
Switching Characteristics^c						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 15V, I_D = 15A, V_{GS} = 4.5V, R_{GEN} = 1\Omega$		41	82	ns
Turn-On Rise Time	t_r			32	64	ns
Turn-Off Delay Time	$t_{d(off)}$			92	184	ns
Turn-Off Fall Time	t_f			30	60	ns
Total Gate Charge	Q_g	$V_{DS} = 15V, I_D = 50A, V_{GS} = 4.5V$		96	125	nC
Gate-Source Charge	Q_{gs}			24		nC
Gate-Drain Charge	Q_{gd}			39		nC
Drain-Source Diode Characteristics and Maximun Ratings						
Drain-Source Diode Forward Current	I_S				115	A
Drain-Source Diode Forward Voltage ^b	V_{SD}	$V_{GS} = 0V, I_S = 30A$			1.2	V
Notes : a.Repetitive Rating : Pulse width limited by maximum junction temperature b.Pulse Test : Pulse Width < 300 μs , Duty Cycle < 2%. c.Guaranteed by design, not subject to production testing. d.L = 1mH, $I_S = 40A, V_{DD} = 24V, R_G = 25\Omega$, Starting $T_J = 25 \text{ C}$						

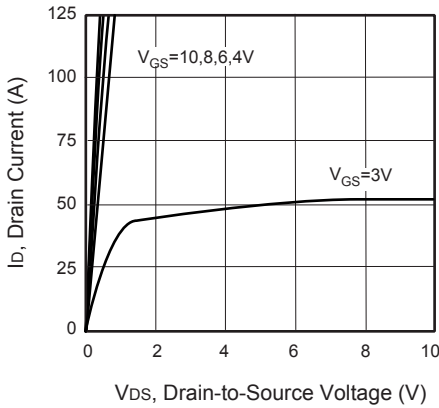


Figure 1. Output Characteristics

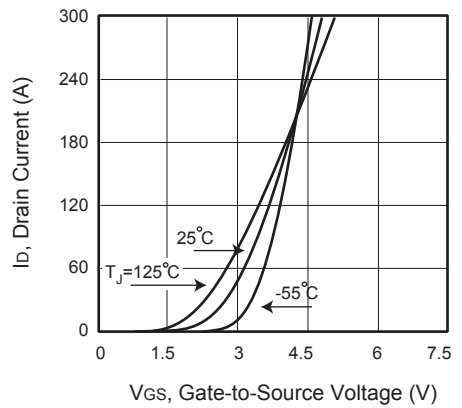


Figure 2. Transfer Characteristics

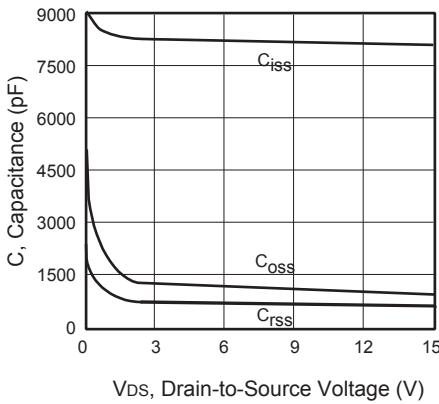


Figure 3. Capacitance

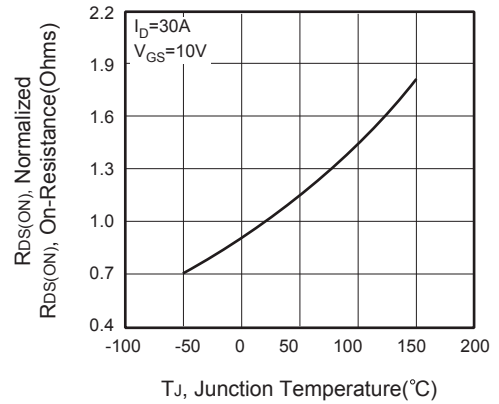


Figure 4. On-Resistance Variation with Temperature

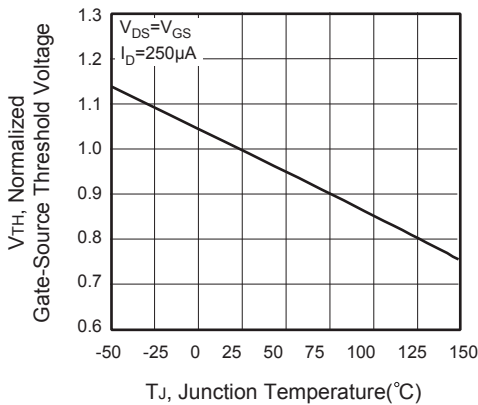


Figure 5. Gate Threshold Variation with Temperature

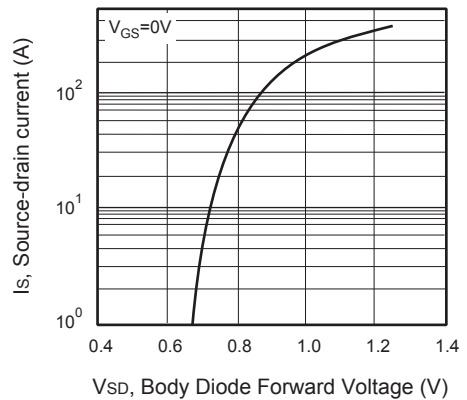


Figure 6. Body Diode Forward Voltage Variation with Source Current

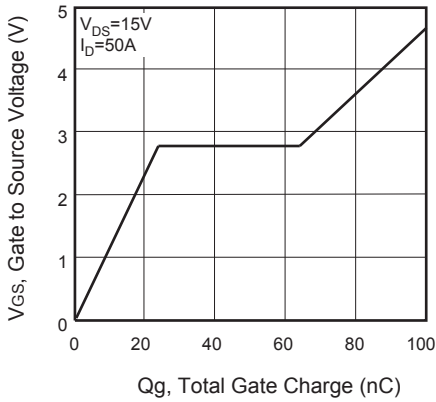


Figure 7. Gate Charge

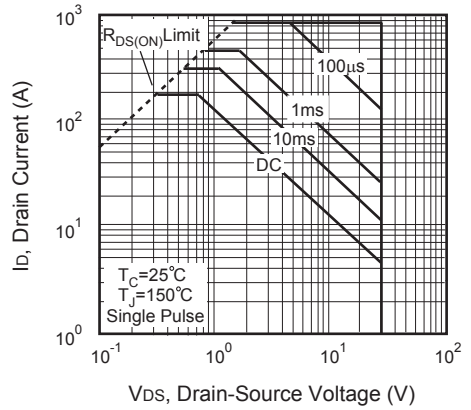


Figure 8. Maximum Safe Operating Area

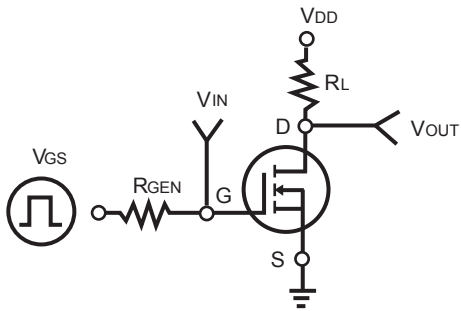


Figure 9. Switching Test Circuit

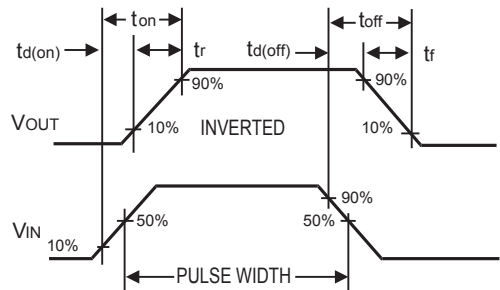


Figure 10. Switching Waveforms

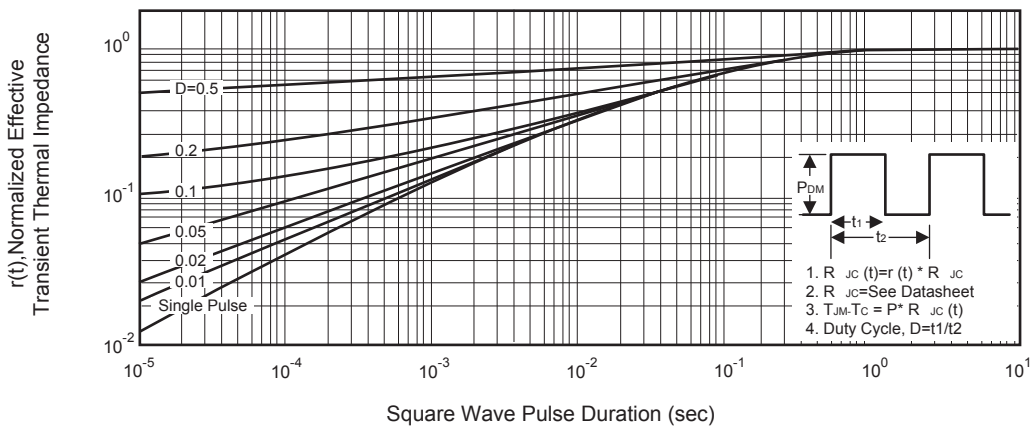


Figure 11. Normalized Thermal Transient Impedance Curve